

### **Amendments to the Claims**

This listing of claims will replace all prior versions of claims in this application.

#### **LISTING OF CLAIMS:**

1. (Currently amended) A[n ion transfer component] skimmer in a mass spectrometer comprising:  
a body having an orifice through which ions can pass, wherein at least a portion of the body comprises titanium metal.
2. (Currently amended) The [ion transfer component] skimmer of claim 1, wherein:  
the entire body comprises titanium metal.
3. (Currently amended) The [ion transfer component] skimmer of claim 1, wherein:  
the at least a portion of the body is coated with titanium metal.
4. (Currently amended) The [ion transfer component] skimmer of claim 1, wherein:  
the at least a portion of the body includes one or more surfaces of the [ion transfer component] skimmer.
5. (Currently amended) The [ion transfer component] skimmer of claim 1, wherein:  
the at least a portion of the body at least partially surrounds and defines the orifice.
6. (Currently amended) The [ion transfer component] skimmer of claim 1, wherein:  
the titanium metal comprises an alloy of titanium.
7. (Currently amended) The [ion transfer component] skimmer of claim 6, wherein:

the alloy of titanium is an alloy of titanium and one or more of the metals in the group consisting of aluminum, vanadium, molybdenum, manganese, iron, platinum, tin, copper, niobium, zirconium, and chromium.

8. (Currently amended) The [ion transfer component] skimmer of claim 1, wherein:  
the titanium metal comprises commercially pure titanium.
9. (Currently amended) The [ion transfer component] skimmer of claim 8, wherein:  
the titanium metal comprises commercial grade I, II, III, or IV titanium.
10. (Cancelled)
11. (Currently amended) The [ion transfer component] skimmer of claim 1[0], wherein:  
the [lens] skimmer is configured such that an electrostatic potential can be applied.
12. (Currently amended) The ion transfer component of claim 1[0], wherein:  
the [lens] skimmer is configured such that an RF potential can be applied.
13. (Cancelled)
14. (Cancelled)
15. (Cancelled)
16. (Cancelled)
17. (Cancelled)
18. (Cancelled)
19. (Cancelled)

20. (Currently Amended) A system for analyzing ions, the system comprising:  
a source of ions for generating ions; and  
a[n ion transfer component] skimmer according to claim 1.
21. (Currently Amended) The system of claim 20, wherein:  
the ions adiabatically expand to form a supersonic free jet, and  
at least a portion of the [ion transfer component] skimmer is disposed in an area of the  
free jet expansion.
22. (Currently Amended) The system of claim 20, wherein:  
the ions adiabatically expand to form a supersonic free jet, and  
at least a portion of the [ion transfer component] skimmer is disposed in a zone of silence  
resulting from the free jet expansion area.
23. (Currently Amended) The system of claim 20, wherein:  
the ions adiabatically expand to form a supersonic free jet, and  
at least a portion of the [ion transfer component] skimmer is disposed outside an area of  
free expansion.
24. (Currently Amended) The system of claim 20, wherein:  
the source of ions comprises an orifice or aperture through which the ions emerge,  
and  
at least a portion of the [ion transfer component] skimmer is disposed such that the  
orifice is disposed opposingly to the emerging ions
25. (Currently Amended) The system of claim 20, wherein:  
the ions generated by the source emerge along an axis, and  
at least a portion of the [ion transfer component] skimmer is disposed at an angle from  
the axis.